

PCTEST ENGINEERING LABORATORY, INC.

7185 Oakland Mills Road, Columbia, MD 21046 USA Tel. 410.290.6652 / Fax 410.290.6654 http://www.pctest.com



HEARING AID COMPATIBILITY

Applicant Name:

Samsung Electronics Co., Ltd. 129, Samsung-ro, Maetan dong, Yeongtong-gu, Suwon-si Gyeonggi-do 16677, Korea Date of Testing: 10/28/2019 - 10/29/2019 Test Site/Location: PCTEST Lab, Columbia, MD, USA Test Report Serial No.: 1M1910220168-01.A3L Date of Issue: 10/31/2019

FCC ID:

A3LSMJ337P

APPLICANT:

SAMSUNG ELECTRONICS CO., LTD.

Scope of Test: Application Type: FCC Rule Part(s): HAC Standard:

DUT Type: Model: Test Device Serial No.: Class II Permissive Change(s): Audio Band Magnetic Testing (T-Coil) Class II Permissive Change CFR §20.19(b) ANSI C63.19-2011 285076 D01 HAC Guidance v05 285076 D02 T-Coil testing for CMRS IP v03 Portable Handset SM-J337P *Pre-Production Sample* [S/N: 58046] See FCC Change Document

C63.19-2011 HAC Category: T4 (SIGNAL TO NOISE CATEGORY)

This report and category pertain only to the Voice over LTE services supported by this wireless portable device. Please refer to the original certification technical report (S/N: 1M1803090037-11-R1.A3L) for data on other modes supported by this device. This wireless portable device has been shown to be hearing-aid compatible for Voice over LTE services, under the above rated category, specified in ANSI/IEEE Std. C63.19-2011 and has been tested in accordance with the specified measurement procedures. Hearing-Aid Compatibility is based on the assumption that all production units will be designed electrically identical to the device tested in this report. Test results reported herein relate only to the item(s) tested. North America bands only.

I attest to the accuracy of data. All measurements reported herein were performed by me or were made under my supervision and are correct to the best of my knowledge and belief. I assume full responsibility for the completeness of these measurements and vouch for the qualifications of all persons taking them.

Randy Ortanez President



FCC ID: A3LSMJ337P		HAC (T-COIL) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Dege 1 of 47
1M1910220168-01.A3L	10/28/2019 - 10/29/2019	Portable Handset		Page 1 of 47
© 2019 PCTEST Engineering Laboratory, Inc.			REV 3.3.M	

REV 3.3.M 08/13/2019

1.	INTRODUCTION	3
2.	DUT DESCRIPTION	4
3.	ANSI C63.19-2011 PERFORMANCE CATEGORIES	5
4.	METHOD OF MEASUREMENT	7
5.	VOLTE TEST SYSTEM SETUP AND DUT CONFIGURATION	. 16
6.	T-COIL TEST SUMMARY	. 20
7.	MEASUREMENT UNCERTAINTY	. 26
8.	EQUIPMENT LIST	. 27
9.	TEST DATA	. 28
10.	CALIBRATION CERTIFICATES	. 35
11.	CONCLUSION	. 42
12.	REFERENCES	. 43
13.	TEST SETUP PHOTOGRAPHS	. 45

FCC ID: A3LSMJ337P		HAC (T-COIL) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Dage 2 of 47
1M1910220168-01.A3L	10/28/2019 - 10/29/2019	Portable Handset		Page 2 of 47
© 2019 PCTEST Engineering Laboratory, Inc.			REV 3.3.M	

1. INTRODUCTION

On July 10, 2003, the Federal Communications Commission (FCC) adopted new rules requiring wireless manufacturers and service providers to provide digital wireless phones that are compatible with hearing aids. The FCC has modified the exemption for wireless phones under the Hearing Aid Compatibility Act of 1998 (HAC Act) in WT Docket 01-309 RM-8658¹ to extend the benefits of wireless telecommunications to individuals with hearing disabilities. These benefits encompass business, social and emergency communications, which increase the value of the wireless network for everyone. An estimated more than 10% of the population in the United States show signs of hearing impairment and of that fraction, almost 80% use hearing aids. Approximately 500 million people worldwide and 30 million people in the United States suffer from hearing loss.

Compatibility Tests Involved:

The standard calls for wireless communications devices to be measured for:

- RF Electric-field emissions
- T-coil mode, magnetic-signal strength in the audio band
- T-coil mode, magnetic-signal frequency response through the audio band
- T-coil mode, magnetic-signal and noise articulation index

The hearing aid must be measured for:

- RF immunity in microphone mode
- RF immunity in T-coil mode

In the following tests and results, this report includes the evaluation for a wireless communications device.



Figure 1-1 Hearing Aid in-vitu

¹ FCC Rule & Order, WT Docket 01-309 RM-8658

FCC ID: A3LSMJ337P		HAC (T-COIL) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Demo 2 of 47
1M1910220168-01.A3L	10/28/2019 - 10/29/2019	Portable Handset		Page 3 of 47
© 2019 PCTEST Engineering Laboratory, Inc.			REV 3.3.M	

2. DUT DESCRIPTION



FCC ID:	A3LSMJ337P
Applicant:	Samsung Electronics Co., Ltd.
	129, Samsung-ro, Maetan dong,
	Yeongtong-gu, Suwon-si
	Gyeonggi-do 16677, Korea
Model:	SM-J337P
Serial Number:	58046
HW Version:	J337PVPU4BSJ2
SW Version:	J337P.06
Antenna:	Internal Antenna
DUT Type:	Portable Handset

Table 2-1 A3LSMJ337P HAC Air Interfaces

Air-Interface	Band (MHz)	Type Transport	HAC Tested	Simultaneous But Not Tested	Name of Voice Service	Audio Codec Evaluated
	835	vo	No ³	Yes: WIFI or BT	CMRS Voice ¹	EVRC
CDMA	1900					
	EvDO	VD	No ³	Yes: WIFI or BT	Google Duo ²	OPUS
	850	vo	No ³	Yes: WIFI or BT	CMRS Voice ¹	EFR
GSM	1900					
	GPRS/EDGE	VD	No ³	Yes: WIFI or BT	Google Duo ²	OPUS
	850					
UMTS	1700	VD	No ³	Yes: WIFI or BT	CMRS Voice ¹	NB AMR
onno	1900					
	HSPA	VD	No ³	Yes: WIFI or BT	Google Duo ²	OPUS
	700 (B12)					
	850 (B5)		Yes Yes: WIFI or BT	Yes Yes: WIFLor BT	VoLTE ¹ , Google Duo ²	VoLTE: NB AMR, WB AMR
LTE (FDD)	850 (B26)	VD				
	1700 (B4)			,	Google Duo: OPUS	
	1900 (B2)					
	1900 (B25)					
LTE (TDD)	2600 (B41)	VD	Yes	Yes: WIFI or BT	VoLTE ¹ , Google Duo ²	VoLTE: NB AMR, WB AMR Google Duo: OPUS
	2450					
	5200 (U-NII 1)					VoWIFI: NB AMR, WB AMR
WIFI	5300 (U-NII 2A)	VD	No ³	Yes: CDMA, GSM, UMTS, or LTE	VoWIFI ² , Google Duo ²	Google Duo: OPUS
	5500 (U-NII 2C)					
	5800 (U-NII 3)					
BT	2450	DT	No	Yes: CDMA, GSM, UMTS, or LTE	N/A	N/A
Type Transport Notes: V0 = Voice Only 1. Reference level in accordance with 7.4.2.1 of ANSI C63.19-2011 and July 2012 C63 VoLTE Interpretation. D = Digital Data - Not intended for Voice Services 2. Reference level is -20dBm0 in accordance with FCC KDB 285076 D02 VD = CMRS and/or IP Voice over Data Transport 3. This report only pertains to Voice Over LTE services. Please refer to the original certification technical report (S/N: 1M18030 11-R1.A3L) for data on other modes supported by this device.						

I. LTE Band Selection

This device supports the following pairs of LTE bands with similar frequencies: LTE B25 & B2 and B26 & B5. These pairs of LTE bands have the same target powers and share the same transmission paths. Since the supported frequency span for the smaller LTE bands are completely covered by the larger LTE bands, only the larger LTE bands (LTE B25 and B26) were evaluated for hearing-aid compliance.

FCC ID: A3LSMJ337P		HAC (T-COIL) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Page 4 of 47
1M1910220168-01.A3L	10/28/2019 - 10/29/2019	Portable Handset		Fage 4 01 47
				REV 3.3.M 08/13/2019

3. ANSI C63.19-2011 PERFORMANCE CATEGORIES

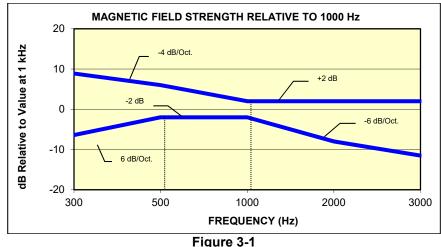
I. MAGNETIC COUPLING

Axial and Radial Field Intensity

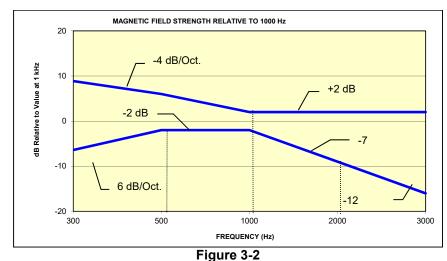
All orientations of the magnetic field, in the axial and radial position along the measurement plane shall be \geq -18 dB(A/m) at 1 kHz in a 1/3 octave band filter per §8.3.1.

Frequency Response

The frequency response of the axial component of the magnetic field shall follow the response curve specified in EIA RS-504-1983, over the frequency range 300 Hz - 3000 Hz per §8.3.2.



Magnetic field frequency response for Wireless Devices with an axial field ≤-15 dB(A/m) at 1 kHz



Magnetic Field frequency response for wireless devices with an axial field that exceeds -15 dB(A/m) at 1 kHz

FCC ID: A3LSMJ337P		HAC (T-COIL) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Dage 5 of 17
1M1910220168-01.A3L	10/28/2019 - 10/29/2019	Portable Handset		Page 5 of 47
© 2019 PCTEST Engineering Laboratory, Inc.			REV 3.3.M	

Signal Quality

The table below provides the signal quality requirement for the intended audio magnetic signal from a wireless device. Only the RF immunity of the hearing aid is measured in T-coil mode. It is assumed that a hearing aid can have no immunity to an interference signal in the audio band, which is the intended reception band for this mode. The only criterion that can be measured is the RF immunity in T-coil mode. This is measured using the same procedure as the audio coupling mode at the same levels.

The signal quality of the axial and radial components of the magnetic field was used to determine the T-coil mode category.

Category	Telephone RF Parameters	
	Wireless Device Signal Quality [(Signal + Noise)-to-noise ratio in dB]	
T1	0 to 10 dB	
T2	10 to 20 dB	
Т3	20 to 30 dB	
T4	4 > 30 dB	
Table 3-1 Magnetic Coupling Parameters		

Note: The FCC limit for SNNR is 20dB and the test data margins will indicate a margin from the FCC limit for compliance.

FCC ID: A3LSMJ337P		HAC (T-COIL) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Dage 6 of 47
1M1910220168-01.A3L	10/28/2019 - 10/29/2019	Portable Handset		Page 6 of 47
© 2019 PCTEST Engineering Laboratory, Inc.			REV 3.3.M	

© 2019 PCTEST Engineering Laboratory, Inc. All rights reserved. Unless otherwise specified, no part of this report may be reproduced or utilized in any part, form or by any means, formor by any means, formor or by any mean

4. METHOD OF MEASUREMENT

I. Test Setup

The equipment was connected as shown in an acoustic/RF hemi-anechoic chamber:

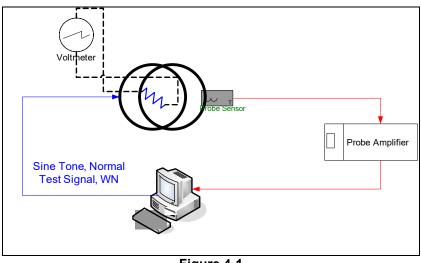
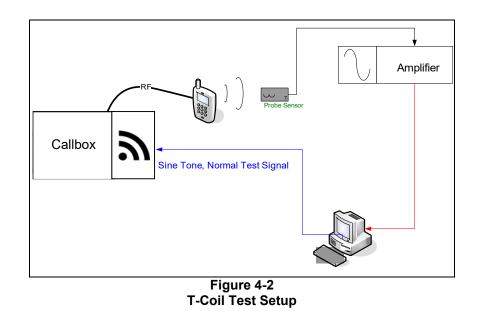


Figure 4-1 Validation Setup with Helmholtz Coil



FCC ID: A3LSMJ337P		HAC (T-COIL) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Dega 7 of 47
1M1910220168-01.A3L	10/28/2019 - 10/29/2019	Portable Handset		Page 7 of 47
© 2019 PCTEST Engineering Laboratory, Inc.			REV 3.3.M	

REV 3.3.M 08/13/2019

II. Scanning Mechanism

Manufacturer:	TEM
Accuracy:	± 0.83 cm/meter
Minimum Step Size:	0.1 mm
Maximum speed	6.1 cm/sec
Line Voltage:	115 VAC
Line Frequency:	60 Hz
Material Composite:	Delrin (Acetal)
Data Control:	Parallel Port
Dynamic Range (X-Y-Z):	45 x 31.75 x 47 cm
Dimensions:	36" x 25" x 38"
Operating Area:	36" x 49" x 55"
Reflections:	< -20 dB (in anechoic chamber)

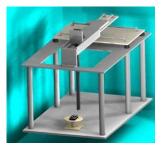


Figure 4-3 RF Near-Field Scanner

III. 3GPP2 Normal Test Signal (Speech)

Manufacturer:	3GPP2 (TIA 1042 §3.3.1)
	Modified-IRS weighted, multi-talker speech signal, 4 Male and 4
Stimulus Type:	Female speakers (alternating)
Single Sample Duration:	51.62 seconds
Activity Level:	77.4%

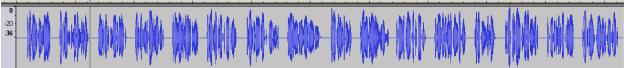
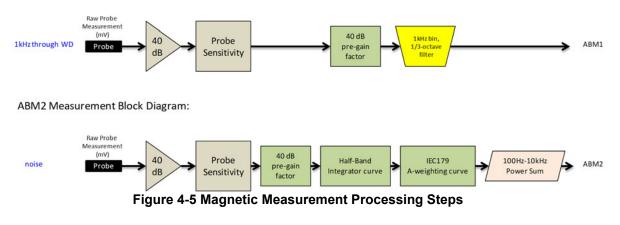


Figure 4-4 Temporal Characteristic of Normal Test Signal

FCC ID: A3LSMJ337P		HAC (T-COIL) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Dage 9 of 47
1M1910220168-01.A3L	10/28/2019 - 10/29/2019	Portable Handset		Page 8 of 47
© 2019 PCTEST Engineering	2019 PCTEST Engineering Laboratory, Inc.			

ABM1 Measurement Block Diagram:



IV. Test Procedure

- 1. Ambient Noise Check per C63.19 §7.3.1
 - Ambient interference was monitored using a Real-Time Analyzer between 100-10,000 Hz with 1/3 octave filtering.
 - b. "A-weighting" and Half-Band Integration was applied to the measurements.
 - c. Since this measurement was measured in the same method as ABM2 measurements, this level was verified to be more than 10 dB below the lowest measurement signal (which is the highest ABM2 measurement for a T4 WD). Therefore the maximum noise level for a T4 WD with an ABM1 = -18 dBA/m is:

- 2. Measurement System Validation (See Figure 4-1)
 - a. The measurement system including the probe, pre-amplifier and acquisition system were validated as an entire system to ensure the reliability of test measurements.
 - b. ABM1 Validation

The magnetic field at the center of the Helmholtz coil is given by the equation (per C63.19 Annex D.10.1):

$$H_{c} = \frac{NI}{r\sqrt{1.25^{3}}} = \frac{N(\frac{V}{R})}{r\sqrt{1.25^{3}}}$$

Where H_c = magnetic field strength in amperes per meter N = number of turns per coil

For the Helmholtz Coil, N=20; r=0.13m; R=10.193Ω and using V=29mV:

$$H_{c} = \frac{20 \cdot (\frac{0.029}{10.193})}{0.13 \cdot \sqrt{1.25^{3}}} = 0.316A/m \approx -10dB(A/m)$$

Therefore a pure tone of 1kHz was applied into the coils such that 29mV was observed across the resistor. The voltmeter used for measurement was verified to be capable of measurements in the audio band range. This theoretically generates an expected field of -10 dB(A/m) in the center of the Helmholtz coil which was used to validate the probe measurement at -10dB(A/m). This was verified to be within \pm 0.5 dB of the -10dB(A/m) value (see Page 24).

FCC ID: A3LSMJ337P		HAC (T-COIL) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Dego 0 of 47
1M1910220168-01.A3L	10/28/2019 - 10/29/2019	Portable Handset		Page 9 of 47
© 2019 PCTEST Engineering	Laboratory Inc.	·		REV 3.3 M

© 2019 PCTEST Engineering Laboratory, Inc.

© 2019 PCTEST Engineering Laboratory, Inc. All rights reserved. Unless otherwise specified, no part of this report may be reproduced or utilized in any part, form or by any means, formor by any means, formor or by any mean

c. Frequency Response Validation

The frequency response through the Helmholtz Coil was verified to be within 0.5 dB relative to 1kHz, between 300 – 3000 Hz using the Normal signal as shown below:



Figure 4-6 Frequency Response Validation

d. ABM2 Measurement Validation

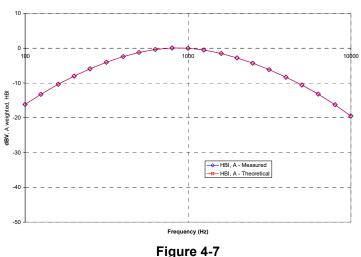
WD noise measurements are filtered with A-weighting and Half-Band Integration over a frequency range of 100Hz – 10kHz to process ABM2 measurements. Below is the verification of the system processing A-weighting and Half-Band integration between system input to output within 0.5 dB of the theoretical result:

	ABM2 Frequency Response Validation				
	HBI, A -	HBI, A -			
f (Hz)	Measured	Theoretical	dB Var.		
	(dB re 1kHz)	(dB re 1kHz)			
100	-16.180	-16.170	-0.010		
125	-13.257	-13.250	-0.007		
160	-10.347	-10.340	-0.007		
200	-8.017	-8.010	-0.007		
250	-5.925	-5.920	-0.005		
315	-4.045	-4.040	-0.005		
400	-2.405	-2.400	-0.005		
500	-1.212	-1.210	-0.002		
630	-0.349	-0.350	0.001		
800	0.071	0.070	0.001		
1000	0.000	0.000	0.000		
1250	-0.503	-0.500	-0.003		
1600	-1.513	-1.510	-0.003		
2000	-2.778	-2.780	0.002		
2500	-4.316	-4.320	0.004		
3150	-6.166	-6.170	0.004		
4000	-8.322	-8.330	0.008		
5000	-10.573	-10.590	0.017		
6300	-13.178	-13.200	0.022		
8000	-16.241	-16.270	0.029		
10000	-19.495	-19.520	0.025		

Table 4-1ABM2 Frequency Response Validation

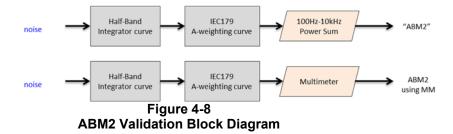
FCC ID: A3LSMJ337P		HAC (T-COIL) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Dega 10 of 47
1M1910220168-01.A3L	10/28/2019 - 10/29/2019	Portable Handset		Page 10 of 47
© 2019 PCTEST Engineering	© 2019 PCTEST Engineering Laboratory, Inc.			

ABM2 Frequency Response Validation (LISTEN)



ABM2 Frequency Response Validation

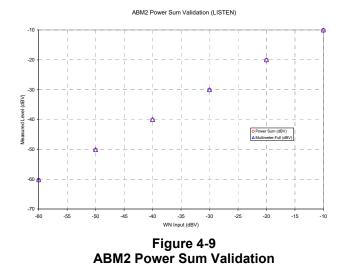
The ABM2 result is a power sum from 100Hz to 10kHz with half-band integration and Aweighting. To verify the power sum measurement, a power sum over the full band was measured and verified to track with the source level (See Figure 4-8). Therefore the setup in this step was used to verify the power sum post-processing for ABM2 measurements. See below block diagram:



The power summed output results for a known input were compared to the multi-meter results to verify any deviation in the post-processing implemented with the power-sum.

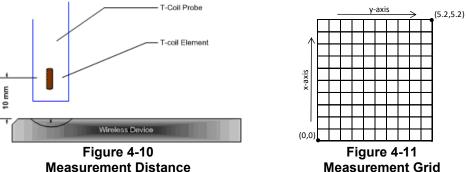
Table 4-2 ABM2 Power Sum Validation					
WN Input (dBV)	Power Sum (dBV)	Multimeter-Full (dBV)	Dev (dB)		
-60	-60.36	-60.2	0.16		
-50	-50.19	-50.13	0.06		
-40	-40.14	-40.03	0.11		
-30	-30.13	-30.01	0.12		
-20	-20.12	-20	0.12		
-10	-10.14	-10	0.14		

FCC ID: A3LSMJ337P		HAC (T-COIL) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Demo 11 of 17
1M1910220168-01.A3L	10/28/2019 - 10/29/2019	Portable Handset		Page 11 of 47
© 2019 PCTEST Engineering	2019 PCTEST Engineering Laboratory, Inc.			



3. Measurement Test Setup

- a. Fine scan above the WD (TEM)
 - i. A multitone signal was applied to the handset such that the phone acoustic output was stable within 1dB over the probe settling time and with the acoustic output level at the C63.19 specified levels (below). The measurement step size was in 2 mm increments at a distance of 10 mm between the surface of the wireless device as shown below (note that in Figure 4-11, the grid is not to scale but merely a graphical representation of the coordinate system in use):



- ii. After scanning, the planar field maximum point was determined. The position of the probe was moved to this location to setup the test using the SoundCheck system.
- iii. These steps were repeated for all T-coil orientations (axial and radial) per Figure 4-13 after a T-coil orientation was fully measured with the SoundCheck system.
- b. Speech Signal Setup to Base Station Simulator
 - i. See Section 5 for more information regarding CMW500 audio level settings for Voice Over LTE (VoLTE).
- C. Real-Time Analyzer (RTA)
 - i. The Real-Time Analyzer was configured to analyze measurements using 1/3 Octave band weighted filtering.
- d. WD Radio Configuration Selection
 - i. The device was chosen to be tested in the worst-case ABM2 condition (LTE configuration information can be found in Section 5.)

FCC ID: A3LSMJ337P		HAC (T-COIL) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Dega 10 of 47
1M1910220168-01.A3L	10/28/2019 - 10/29/2019	Portable Handset		Page 12 of 47
© 2019 PCTEST Engineering Laboratory, Inc.				REV 3.3.M

- 4. Signal Quality Data Analysis
 - a. Narrow-band Magnetic Intensity
 - i. The standard specifies a 1kHz 1/3 octave band minimum field intensity for a sine tone. The ABM1 measurements were evaluated at 1kHz with 1/3 octave band filtering over an averaged period of 10 seconds.
 - b. Frequency Response
 - i. The appropriate frequency response curve was measured to curves in Figure 3-1 or Figure 3-2 between 300 3000 Hz using digital linear averaging (limit lines chosen according to measurement found in step 4a). A linear average over 3x the length of the artificial voice signal (3x sampling) was performed. A 10 second delay was configured in the measurement process of the stimulus to ensure handset vocoder latency effects and echo cancellation devices (if any) were appropriately stabilized during measurements.
 - ii. The appropriate post-processing was applied according to the system processing chain illustrated in Figure 4-6. All R10 frequencies were plotted with respect to 0dB at 1kHz value and aligned with respect to the EIA-504 mask.
 - iii. The margin is represented by the closest measured data point on the curve to the EIA-504 limit lines, in dB.
 - c. Signal Quality Index
 - i. Ensuring the WD was at maximum RF power, maximum volume, backlight off, display on, maximum contrast setting, keypad lights on (when possible) with no audio signal through the vocoder, the WD was measured over at least 100 Hz 10,000 Hz, maximized over 5 seconds with a 50ms sample time for the ABM2 measurement (5 second time period is used in noise measurements under standards such as IEEE 269, etc.).
 - ii. After applying half-band integration and A-weighting to the result, a power sum was applied over each 1/3 octave bandwidth frequency for an ABM2 value.
 - iii. This result was subtracted from the ABM1 result in step a, to obtain the Signal Quality.

V. Test Setup

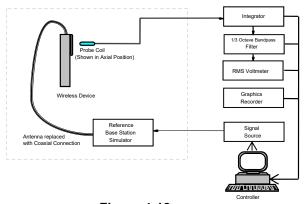


Figure 4-12 Audio Magnetic Field Test Setup

Environmental conditions such as temperature and relative humidity are monitored to ensure there are no impacts on system specifications. Proper voltage and power line frequency conditions are maintained with three phase power sources. Environmental noise and reflections are monitored through system checks.

FCC ID: A3LSMJ337P		HAC (T-COIL) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Dawa 40 af 47
1M1910220168-01.A3L	10/28/2019 - 10/29/2019	Portable Handset		Page 13 of 47
© 2019 PCTEST Engineering	© 2019 PCTEST Engineering Laboratory, Inc.			

VI. Deviation from C63.19 Test Procedure

Non-conducted RF connection due to inaccessible RF ports.

VII. Air Interface Technologies Tested

All air interfaces which support voice capabilities over a managed CMRS or pre-installed OTT VoIP applications were tested for T-coil unless otherwise noted. See Table 2-1 for more details regarding which modes were tested.

VIII. Wireless Device Channels and Frequencies

1. 4G (LTE) Modes

The middle channel for every band and bandwidth combination was tested for each probe orientation. The band and bandwidth combination from each probe orientation resulting in the worst-case SNNR was additionally tested using low and high channels for that band and bandwidth combination. Low-mid and mid-high channels are additionally tested for LTE TDD. See Tables 6-2 to 6-7 for LTE bandwidths and channels.

FCC ID: A3LSMJ337P		HAC (T-COIL) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Dage 14 of 17
1M1910220168-01.A3L	10/28/2019 - 10/29/2019	Portable Handset		Page 14 of 47
© 2019 PCTEST Engineering	© 2019 PCTEST Engineering Laboratory. Inc.			

REV 3.3.M 08/13/2019

IX. Test Flow

The flow diagram below was followed (From C63.19):

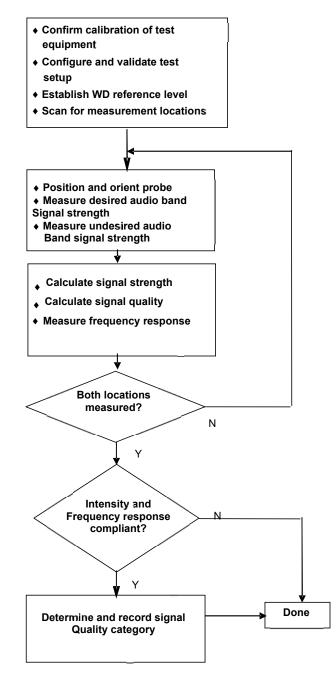


Figure 4-13 C63.19 T-Coil Signal Test Process

FCC ID: A3LSMJ337P		HAC (T-COIL) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Dega 15 of 17
1M1910220168-01.A3L	10/28/2019 - 10/29/2019	Portable Handset		Page 15 of 47
© 2019 PCTEST Engineering	2019 PCTEST Engineering Laboratory, Inc.			

^{08/13/2019}

5. VOLTE TEST SYSTEM SETUP AND DUT CONFIGURATION

I. Test System Setup for VoLTE over IMS T-coil Testing

1. Equipment Setup

The general test setup used for VoLTE over IMS is shown below. The callbox used when performing VoLTE over IMS T-coil measurements is a CMW500. The Data Application Unit (DAU) of the CMW500 was used to simulate the IP Multimedia Subsystem (IMS) server.

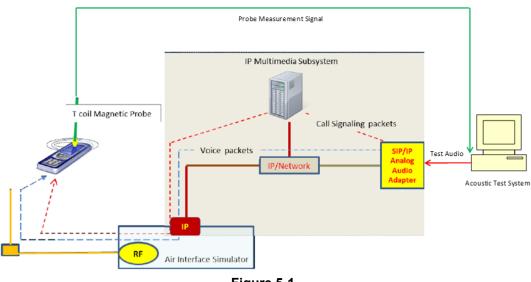


Figure 5-1 Test Setup for VoLTE over IMS T-Coil Measurements

2. Audio Level Settings

According to the July 2012 interpretations by the C63 Committee regarding the appropriate audio levels to be used for VoLTE over IMS T-coil testing, -16dBm0 shall be used for the normal speech input level^{*}. The CMW500 base station simulator was manually configured to ensure that the settings for speech input and full scale levels resulted in the -16dBm0 speech input level to the DUT for the VoLTE over IMS connection.

* http://c63.org/documents/misc/posting/new_interpretations.htm

FCC ID: A3LSMJ337P		HAC (T-COIL) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Dage 16 of 17
1M1910220168-01.A3L	10/28/2019 - 10/29/2019	Portable Handset		Page 16 of 47
2019 PCTEST Engineering Laboratory, Inc.				REV 3.3.M

II. DUT Configuration for VoLTE over IMS T-coil Testing

1. Radio Configuration

An investigation was performed to determine the modulation and RB configuration to be used for testing. The effects of modulation and RB configuration were found to be independent of band and bandwidth; therefore, only one band and bandwidth were used for this investigation. 16QAM, 1RB, 99% RB offset was used for the testing as the worst-case configuration for the handset. See below table for SNNR comparison between different radio configurations:

Band	Frequency [MHz]	Channel	Bandwidth [MHz]	Modulation	RB Size	RB Offset	ABM1 [dB(A/m)]	ABM2 [dB(A/m)]	SNNR [dB]				
12	707.5	23095	10	QPSK	1	0	2.67	-54.15	56.82				
12	707.5	23095	10	QPSK	1	25	2.78	-53.96	56.74				
12	707.5	23095	10	QPSK	1	49	2.69	-52.07	54.76				
12	707.5	23095	10	QPSK	25	0	2.84	-54.80	57.64				
12	707.5	23095	10	QPSK	25	12	2.74	-55.99	58.73				
12	707.5	23095	10	QPSK	25	25	2.47	-56.44	58.91				
12	707.5	23095	10	QPSK	50	0	2.71	-55.77	58.48				
12	707.5	23095	10	16QAM	1	0	2.72	-49.27	51.99				
12	707.5	23095	10	16QAM	1	25	2.60	-49.70	52.30				
12	707.5	23095	10	16QAM	1	49	2.53	-48.20	50.73				
12	707.5	23095	10	16QAM	25	0	2.55	-54.14	56.69				
12	707.5	23095	10	16QAM	25	12	2.67	-55.54	58.21				
12	707.5	23095	10	16QAM	25	25	2.84	-55.48	58.32				
12	707.5	23095	10	16QAM	50	0	2.73	-55.74	58.47				

Table 5-1 VoLTE over IMS SNNR by Radio Configuration

2. Codec Configuration

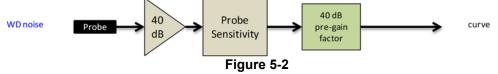
An investigation was performed to determine the audio codec configuration to be used for testing. The effects of codec configuration were found to be independent of band and bandwidth; therefore, only one band and bandwidth were used for this investigation. The WB AMR 6.60kbps setting was used for the audio codec on the CMW500 for VoLTE over IMS T-coil testing. See below table for comparisons between different codecs and codec data rates:

AMR Codec Investigation – Vol I E over IMS											
Codec Setting:	WB AMR 23.85kbps	WB AMR 6.60kbps	NB AMR 12.2kbps	NB AMR 4.75kbps	Orientation	Band / BW	Channel				
ABM1 (dBA/m)	2.89	2.74	6.24	5.48			23095				
ABM2 (dBA/m)	-49.19	-49.00	-49.63	-49.56	Avial	LTE B12 10MHz					
Frequency Response	Pass	Pass	Pass	Pass	- Axial						
S+N/N (dB)	52.08	51.74	55.87	55.04							

		Table 5-	2						
AN	AMR Codec Investigation – VoLTE over IMS								

Mute on; Backlight off; Max Volume; Max Contrast

TPC = "Max Power"



Audio Band Magnetic Curve Measurement Block Diagram

FCC ID: A3LSMJ337P		HAC (T-COIL) TEST REPORT	SAMSUNG	Approved by: Quality Manager				
Filename:	Test Dates:	DUT Type:		Dogo 17 of 47				
1M1910220168-01.A3L	10/28/2019 - 10/29/2019	Portable Handset		Page 17 of 47				

© 2019 PCTEST Engineering Laboratory, Inc.

3. LTE TDD Uplink-Downlink Configuration Investigation for VoLTE over IMS

An investigation was performed to determine the worst-case Uplink-Downlink configuration for VoLTE over IMS T-Coil testing.

Per 3GPP TS 36.211, the total frame length for each TDD radio frame of length $T_f = 307200 \cdot T_s = 10 \text{ ms}$, where T_s is a number of time units equal to 1/(15000 x 2048) seconds. Additionally, each radio frame consists of 10 subframes, each of length $30720 \cdot T_s = 1 \text{ ms}$, and subframes can be designated as uplink (U), downlink (D), or special subframe (S), depending on the Uplink-Downlink configuration as indicated in Table 4.2-2 of 3GPP TS 36.211. In the transmission duty factor calculation, the special subframe configuration with the shortest UpPTS duration within the special subframe is used and will be applied for measurement. From 3GPP TS 36.211 Table 4.2-1, the shortest UpPTS is 2192 \cdot Ts which occurs in the normal cyclic prefix and special subframe configuration 4.

See table below outlining the calculated transmission duty cycles for each Uplink-Downlink configuration:

Uplink-downlink configuration	Downlink-to-Uplink	Downlink-to-Uplink Subframe numb Switch-point periodicity						per			Calculated Transmission	
configuration	Switch-point periodicity	0	1	2	3	4	5	6	7	8	9	Duty Cycle (%)
0	5 ms	D	S	U	U	U	D	S	U	U	U	61.4%
1	5 ms	D	S	U	U	D	D	S	U	U	D	41.4%
2	5 ms	D	S	U	D	D	D	S	U	D	D	21.4%
3	10 ms	D	S	U	U	U	D	D	D	D	D	30.7%
4	10 ms	D	S	U	U	D	D	D	D	D	D	20.7%
5	10 ms	D	S	U	D	D	D	D	D	D	D	10.7%
6	5 ms	D	S	U	U	U	D	S	U	U	D	51.4%

Table 5-3 Uplink-Downlink Configurations for Type 2 Frame Structures

a. Power Class 3 Uplink-Downlink Configuration Investigation

Power class 3 was evaluated with the following radio configuration: channel 40620, 20MHz BW, 16QAM, 1RB, 0RB Offset. For Power Class 3, all configurations (0-6) are supported. The configuration which resulted in the worst SNNR was used for full testing. Uplink-Downlink configuration 1 was used as the worst-case configuration for Power Class 3 VoLTE over IMS T-Coil testing. See table below for the SNNR comparison between each Uplink-Downlink configuration:

Frequency [MHz]	Channel	Bandwidth [MHz]	Modulation	RB Size	RB Offset	UL-DL Configuration	ABM1 [dB(A/m)]	ABM2 [dB(A/m)]	SNNR [dB]				
2593.0	40620	20	16QAM	1	0	0	2.87	-40.85	43.72				
2593.0	40620	20	16QAM	1	0	1	2.77	-40.62	43.39				
2593.0	40620	20	16QAM	1	0	2	2.72	-41.18	43.90				
2593.0	40620	20	16QAM	1	0	3	2.91	-42.43	45.34				
2593.0	40620	20	16QAM	1	0	4	2.95	-42.28	45.23				
2593.0	40620	20	16QAM	1	0	5	2.92	-42.61	45.53				
2593.0	40620	20	16QAM	1	0	6	2.89	-41.48	44.37				

Table 5-4 Power Class 3 VoLTE over IMS SNNR by UL-DL Configuration

FCC ID: A3LSMJ337P		HAC (T-COIL) TEST REPORT	SAMSUNG	Approved by: Quality Manager				
Filename:	Test Dates:	DUT Type:		Dega 19 of 47				
1M1910220168-01.A3L	10/28/2019 - 10/29/2019	Portable Handset		Page 18 of 47				
© 2019 PCTEST Engineering Laboratory. Inc.								

b. Power Class 2 Uplink-Downlink Configuration Investigation

Power Class 2 was evaluated with the following radio configuration: channel 40620, 20MHz BW, 16QAM, 1RB, 0RB Offset. For Power Class 2, configurations 1-5 are supported. The configuration which resulted in the worst SNNR was used for full testing. Uplink-Downlink configuration 1 was used as the worst-case configuration for Power Class 2 VoLTE over IMS T-Coil testing. See table below for the SNNR comparison between each Uplink-Downlink configuration:

Frequency [MHz]	Channel	Bandwidth [MHz]	Modulation	RB Size	RB Offset	UL-DL Configuration	ABM1 [dB(A/m)]	ABM2 [dB(A/m)]	SNNR [dB]			
2593.0	40620	20	16QAM	1	0	1	2.53	-38.12	40.65			
2593.0	40620	20	16QAM	1	0	2	2.99	-38.18	41.17			
2593.0	40620	20	16QAM	1	0	3	2.77	-40.60	43.37			
2593.0	40620	20	16QAM	1	0	4	2.99	-40.86	43.85			
2593.0	40620	20	16QAM	1	0	5	2.96	-40.99	43.95			

Table 5-5
Power Class 2 VoLTE over IMS SNNR by UL-DL Configuration

Note: LTE TDD B41 Power Class 2 only supports UL-DL configurations 1-5, not 0 or 6.

c. Conclusion

Per the investigations above, UL-DL Configuration 1 was used to evaluate both Power Class 3 and Power Class 2 VoLTE over IMS.

FCC ID: A3LSMJ337P		HAC (T-COIL) TEST REPORT	SAMSUNG	Approved by: Quality Manager						
Filename:	Test Dates:	DUT Type:		Page 19 of 47						
1M1910220168-01.A3L	10/28/2019 - 10/29/2019	Portable Handset								
© 2019 PCTEST Engineering	© 2019 PCTEST Engineering Laboratory, Inc.									

T-COIL TEST SUMMARY 6.

Consolidated Tabled Results											
		Freq. Re Mai	esponse rgin	Magnetic Intensity Verdict		FCC SNNR Verdict		Margin from FCC Limit	C63.19-2011		
C63.19 Section		8.3	3.2	8.3.1		8.3.4		(dB)	Rating		
		Axial	Radial	Axial	Radial	Axial	Radial				
	B12	PASS	NA	PASS	PASS	PASS	PASS).96 T4		
	B26	PASS	NA	PASS	PASS	PASS	PASS				
LTE FDD	B4	PASS	NA	PASS	PASS	PASS	PASS	-29.90			
	B25	PASS	NA	PASS	PASS	PASS	PASS				
	B41 (PC3)	PASS	NA	PASS	PASS	PASS	PASS	20.27	T4		
LTE TDD	B41 (PC2)	PASS	NA	PASS	PASS	PASS	PASS	-20.37	T4		

Table 6-1

FCC ID: A3LSMJ337P		HAC (T-COIL) TEST REPORT	SAMSUNG	Approved by: Quality Manager					
Filename:	Test Dates:	DUT Type:		Dama 00 of 47					
1M1910220168-01.A3L	10/28/2019 - 10/29/2019	Portable Handset		Page 20 of 47					
© 2019 PCTEST Engineering	2019 PCTEST Engineering Laboratory, Inc.								

08/13/2019

I. Raw Handset Data

Mode	Orientation	Bandwidth	Channel	ABM1 [dB(A/m)]	ABM2 [dB(A/m)]	Ambient Noise [dB(A/m)]	Frequency Response Margin (dB)	S+N/N (dB)	FCC Limit (dB)	Margin from FCC Limit (dB)	C63.19-2011 Rating	Test Coordinates
Articl	10MHz	23095	2.64	-48.03	-	1.19	50.67	20.00	-30.67	T4		
	Axial	5MHz	23095	2.85	-47.54	-61.30	1.26	50.39	20.00	-30.39	T4	2.6, 2.4
	Axiai	3MHz	23095	2.85	-47.88		1.36	50.73	20.00	-30.73	T4	2.0, 2.4
LTE Band 12		1.4MHz	23095	2.86	-48.03		1.27	50.89	20.00	-30.89	T4	
LIE Band 12		10MHz	23095	-4.28	-55.08			50.80	20.00	-30.80	T4	
	Radial	5MHz	23095	-4.55	-55.16	-61.00	N/A	50.61	20.00	-30.61	T4	2.6, 1.6
		3MHz	23095	-4.29	-55.54		N/A	51.25	20.00	-31.25	T4	2.0, 1.0
	1.4MHz	23095	-4.13	-56.63]		52.50	20.00	-32.50	T4		

Table 6-2Raw Data Results for LTE B12

Table 6-3 Raw Data Results for LTE B26

Mode	Orientation	Bandwidth	Channel	ABM1 [dB(A/m)]	ABM2 [dB(A/m)]	Ambient Noise [dB(A/m)]	Frequency Response Margin (dB)	S+N/N (dB)	FCC Limit (dB)	Margin from FCC Limit (dB)	C63.19-2011 Rating	Test Coordinates
Axial	15MHz	26865	2.62	-48.35		1.14	50.97	20.00	-30.97	T4		
		10MHz	26865	2.72	-47.84	-61.30	1.15	50.56	20.00	-30.56	T4	
	Axial	5MHz	26865	2.79	-47.76		1.21	50.55	20.00	-30.55	T4	2.6, 2.4
		3MHz	26865	2.74	-48.60		1.18	51.34	20.00	-31.34	T4	
LTE Band 26		1.4MHz	26865	2.72	-48.03		1.10	50.75	20.00	-30.75	T4	
LIE Danu 20		15MHz	26865	-4.50	-55.57			51.07	20.00	-31.07	T4	
		10MHz	26865	-4.45	-55.00			50.55	20.00	-30.55	T4	
	Radial	5MHz	26865	-4.19	-56.23	-61.00	N/A	52.04	20.00	-32.04	T4	2.6, 1.6
		3MHz	26865	-4.29	-55.68			51.39	20.00	-31.39	T4	
		1.4MHz	26865	-4.30	-56.21			51.91	20.00	-31.91	T4	

Table 6-4 Raw Data Results for LTE B4

Mode	Orientation	Bandwidth	Channel	ABM1 [dB(A/m)]	ABM2 [dB(A/m)]	Ambient Noise [dB(A/m)]	Frequency Response Margin (dB)	S+N/N (dB)	FCC Limit (dB)	Margin from FCC Limit (dB)	C63.19-2011 Rating	Test Coordinates	
		20MHz	20300	2.42	-48.91		1.02	51.33	20.00	-31.33	T4		
Axial		20MHz	20175	2.48	-47.48		1.25	49.96	20.00	-29.96	T4		
		20MHz	20050	2.42	-50.09	-61.30	1.17	52.51	20.00	-32.51	T4		
	Avial	15MHz	20175	2.56	-47.55		1.19	50.11	20.00	-30.11	T4	2.6, 2.4	
	Axidi	10MHz	20175	2.75	-48.00		1.19	50.75	20.00	-30.75	T4	2.0, 2.4	
		5MHz	20175	2.70	-48.22		1.19	50.92	20.00	-30.92	T4		
		3MHz	20175	2.76	-48.66		1.19	51.42	20.00	-31.42	T4		
LTE Band 4		1.4MHz	20175	2.48	-48.80		1.21	51.28	20.00	-31.28	T4		
LIE Ballu 4		20MHz	20300	-4.18	-55.54	-		51.36	20.00	-31.36	T4		
		20MHz	20175	-4.16	-54.24			50.08	20.00	-30.08	T4		
		20MHz	20050	-4.31	-56.93			52.62	20.00	-32.62	T4		
	Dedial	15MHz	20175	-4.40	-55.14	61.00	NVA	50.74	20.00	-30.74	T4	26.16	
	Radial	10MHz	20175	-4.18	-55.76	-61.00	N/A	51.58	20.00	-31.58	T4	2.6, 1.6	
		5MHz	20175	-4.44	-56.26	-		51.82	20.00	-31.82	T4		
		3MHz	20175	-4.47	-55.77			51.30	20.00	-31.30	T4		
		1.4MHz	20175	-4.38	-56.81			52.43	20.00	-32.43	T4		

Table 6-5 Raw Data Results for LTE B25

Mode	Orientation	Bandwidth	Channel	ABM1 [dB(A/m)]	ABM2 [dB(A/m)]	Ambient Noise [dB(A/m)]	Frequency Response Margin (dB)	S+N/N (dB)	FCC Limit (dB)	Margin from FCC Limit (dB)	C63.19-2011 Rating	Test Coordinates	
		20MHz	26365	2.96	-47.25		1.31	50.21	20.00	-30.21	T4		
		15MHz	26365	2.74	-48.13		1.24	50.87	20.00	-30.87	T4		
	Axial	10MHz 26365 2.70 -48.71 -61.30	1.17	51.41	20.00	-31.41	T4	2.6, 2.4					
	Axiai	5MHz	26365	2.58	-49.22	-61.30	-01.30	1.14	51.80	20.00	-31.80	T4	2.0, 2.4
		3MHz	26365	2.46	-49.54		1.36	52.00	20.00	-32.00	T4		
LTE Band 25		1.4MHz	26365	2.48	-48.99		1.18	51.47	20.00	-31.47	T4		
LIE Danu 25		20MHz	26365	-4.30	-55.08			50.78	20.00	-30.78	T4		
		15MHz	26365	-4.03	-55.18			51.15	20.00	-31.15	T4		
	Radial	10MHz	26365	-4.21	-55.61	61.00	N/A	51.40	20.00	-31.40	T4	2.6, 1.6	
	Raulai	5MHz	26365	-4.05	-55.85		IVA	51.80	20.00	-31.80	T4	2.0, 1.0	
		3MHz	26365	-4.41	-56.16			51.75	20.00	-31.75	T4		
		1.4MHz	26365	-4.18	-55.35			51.17	20.00	-31.17	T4		

FCC ID: A3LSMJ337P		HAC (T-COIL) TEST REPORT	SAMSUNG	Approved by: Quality Manager		
Filename: Test Dates:		DUT Type:		Dage 01 of 47		
1M1910220168-01.A3L	10/28/2019 - 10/29/2019 Portable Handset			Page 21 of 47		

© 2019 PCTEST Engineering Laboratory, Inc.

REV 3.3.M 08/13/2019

Mode	Orientation	Bandwidth	Channel	ABM1 [dB(A/m)]	ABM2 [dB(A/m)]	Ambient Noise [dB(A/m)]	Frequency Response Margin (dB)	S+N/N (dB)	FCC Limit (dB)	Margin from FCC Limit (dB)	C63.19-2011 Rating	Test Coordinates
		20MHz	40620	2.70	-41.03		1.27	43.73	20.00	-23.73	T4	
	Axial	15MHz	40620	2.82	-41.45	-61.30	1.16	44.27	20.00	-24.27	T4	2.6, 2.4
	Axiai	10MHz	40620	2.68	-41.34		1.08	44.02	20.00	-24.02	T4	2.0, 2.4
LTE Band 41		5MHz	40620	2.65	-41.67		1.23	44.32	20.00	-24.32	T4	
LIE Ballu 41		20MHz	40620	-4.30	-54.95			50.65	20.00	-30.65	T4	
	Radial	15MHz	40620	-4.28	-55.94	-61.00	N/A	51.66	20.00	-31.66	T4	2.6, 1.6
	Raulai	10MHz	40620	-4.43	-56.25	-61.00 N/A	IVA	51.82	20.00	-31.82	T4	2.0, 1.0
	5MHz	40620	-4.17	-55.49			51.32	20.00	-31.32	T4		

Table 6-6Raw Data Results for LTE B41 Power Class 3

Table 6-7 Raw Data Results for LTE B41 Power Class 2

Mode	Orientation	Bandwidth	Channel	ABM1 [dB(A/m)]	ABM2 [dB(A/m)]	Ambient Noise [dB(A/m)]	Frequency Response Margin (dB)	S+N/N (dB)	FCC Limit (dB)	Margin from FCC Limit (dB)	C63.19-2011 Rating	Test Coordinates
		20MHz	40620	2.93	-37.90		1.29	40.83	20.00	-20.83	T4	
		15MHz	40620	2.97	-37.92		1.08	40.89	20.00	-20.89	T4	
	10MHz	41490	2.95	-39.25		1.17	42.20	20.00	-22.20	T4		
	Axial	10MHz	41055	2.72	-39.44	-61.30	1.23	42.16	20.00	-22.16	T4	2.6, 2.4
Axiai	Axiai	10MHz	40620	2.95	-37.42		1.23	40.37	20.00	-20.37	T4	2.0, 2.4
		10MHz	40185	2.85	-38.35		1.28	41.20	20.00	-21.20	T4	
		10MHz	39750	2.87	-39.64		1.12	42.51	20.00	-22.51	T4	
LTE Band 41		5MHz	40620	2.65	-38.02		1.21	40.67	20.00	-20.67	T4	
LIE Banu 41		20MHz	40620	-4.16	-53.16	-		49.00	20.00	-29.00	T4	
		15MHz	40620	-4.21	-53.33			49.12	20.00	-29.12	T4	
		10MHz	41490	-4.18	-53.43			49.25	20.00	-29.25	T4	
	Radial	10MHz	41055	-4.21	-54.42	61.00	N/A	50.21	20.00	-30.21	T4	2.6, 1.6
	Radiai	10MHz	40620	-4.33	-53.14	-61.00	IWA	48.81	20.00	-28.81	T4	2.0, 1.0
		10MHz	40185	-4.26	-52.83	-		48.57	20.00	-28.57	T4	
		10MHz	39750	-4.17	-54.63				50.46	20.00	-30.46	T4
		5MHz	40620	-4.31	-53.79			49.48	20.00	-29.48	T4	

II. Test Notes

A. General

- 1. Phone Condition: Mute on; Backlight off; Max Volume; Max Contrast
- 2. 'Radial' orientation refers to radial transverse.
- 3. Hearing Aid Mode (**Phone→Settings→Other Call Settings→Hearing aids**) was set to ON for Frequency Response compliance
- 4. Speech Signal: 3GPP2 Normal Test Signal
- 5. Bluetooth and WIFI were disabled while testing 4G modes.
- 6. The Margin from FCC limit column indicates a margin from the FCC limit for compliance (T4).

B. LTE FDD

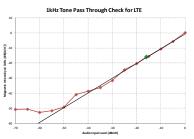
- 1. Power Configuration: TPC = "Max Power"
- 2. Radio Configuration: 16QAM, 1RB, 99% RB offset
- 3. Vocoder Configuration: WB AMR 6.60kbps
- 4. The worst-case band and bandwidth combination for each probe orientation is additionally tested on the low and high channels for those combinations. LTE Band 4 at 20MHz is the worst-case for the Axial and Radial probe orientation.

FCC ID: A3LSMJ337P		HAC (T-COIL) TEST REPORT	SAMSUNG	Approved by: Quality Manager		
Filename:	Test Dates:	DUT Type:		Dega 22 of 47		
1M1910220168-01.A3L	10/28/2019 - 10/29/2019	Portable Handset		Page 22 of 47		
© 2019 PCTEST Engineering Laboratory. Inc.						

C. LTE TDD

- 1. Power Configuration: TPC = "Max Power"
- 2. Radio Configuration: 16QAM, 1RB, 99% RB offset
- 3. Power Class 3 Uplink-Downlink configuration: 1
- 4. Power Class 2 Uplink-Downlink configuration: 1
- 5. Vocoder Configuration: WB AMR 6.60kbps
- 6. The worst-case band and bandwidth combination for each probe orientation is additionally tested on the low, low-mid, high-mid, and high channels for those combinations. LTE Band 41 (Power Class 2) at 10MHz is the worst-case for the Axial and Radial probe orientation.

III. 1 kHz Vocoder Application Check



This model was verified to be within the linear region for ABM1 measurements at -16 dBm0 for VoLTE over IMS. This measurement was taken in the axial configuration above the maximum location.

FCC ID: A3LSMJ337P		HAC (T-COIL) TEST REPORT	SAMSUNG	Approved by: Quality Manager		
Filename:	Test Dates:	DUT Type:		Dage 22 of 47		
1M1910220168-01.A3L	10/28/2019 - 10/29/2019	Portable Handset		Page 23 of 47		
© 2019 PCTEST Engineering Laboratory, Inc.						

08/13/2019

IV. T-Coil Validation Test Results

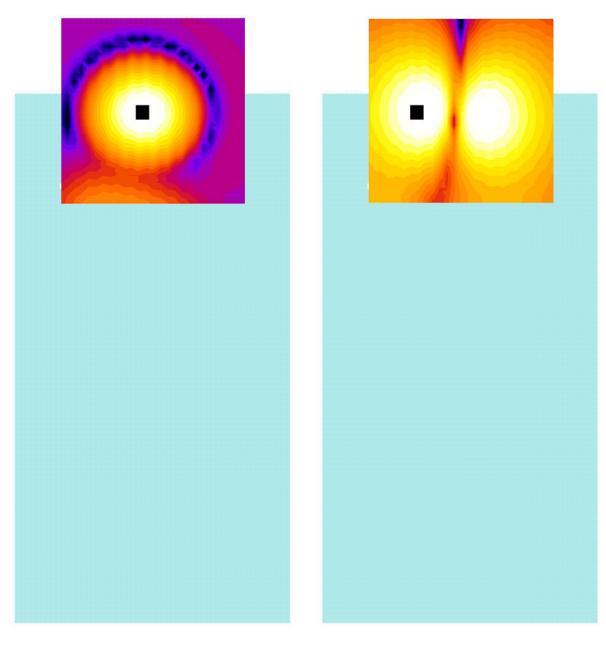
			Mondiat
ltem	Target	Result	Verdict
Axial			
Magnetic Intensity, -10 dBA/m	-10 ± 0.5 dB	-9.771	PASS
Environmental Noise	< -58 dBA/m	-61.30	PASS
Frequency Response, from limits	> 0 dB	0.50	PASS
Radial			
Magnetic Intensity, -10 dBA/m	-10 ± 0.5 dB	-10.077	PASS
Environmental Noise	< -58 dBA/m	-61.00	PASS
Frequency Response, from limits	> 0 dB	0.70	PASS

 Table 6-8

 Helmholtz Coil Validation Table of Results

FCC ID: A3LSMJ337P		HAC (T-COIL) TEST REPORT	SAMSUNG	Approved by: Quality Manager		
Filename:	Test Dates:	DUT Type:	Туре:			
1M1910220168-01.A3L	10/28/2019 - 10/29/2019	Portable Handset		Page 24 of 47		
© 2019 PCTEST Engineering Laboratory, Inc.						





Axial Radial (Transverse) Figure 6-1 T-Coil Scan Overlay Magnetic Field Distributions

Notes:

- 1. Final measurement locations are indicated by a cursor on the contour plots.
- 2. See Test Setup Photographs for actual WD overlay.

FCC ID: A3LSMJ337P		HAC (T-COIL) TEST REPORT	SAMSUNG	Approved by: Quality Manager		
Filename:	Test Dates:	DUT Type:	DUT Type:			
1M1910220168-01.A3L	10/28/2019 - 10/29/2019	Portable Handset		Page 25 of 47		
© 2019 PCTEST Engineering Laboratory, Inc.						

© 2019 PCTEST Engineering Laboratory, Inc. All rights reserved. Unless otherwise specified, no part of this report may be reproduced or utilized in any part, form or by any means, formor by any means, formor or by any mean

7. MEASUREMENT UNCERTAINTY

Contribution	Data +/- %	Data +/- dB	Data Type	Probability distribution	Divisor	Standard uncertainty	Standard Uncertainty (dB)
ABM Noise	7.0%	0.29	Std. Dev.	Normal k=1	1.00	7.0%	
RF Reflections	4.7%	0.20	Specification	Rectangular	1.73	2.7%	
Reference Signal Level	12.2%	0.50	Specification	Rectangular	1.73	7.0%	
Positioning Accuracy	10.0%	0.41	Uncertainty	Rectangular	1.73	5.8%	
Probe Coil Sensitivity	12.2%	0.50	Specification	Rectangular	1.73	7.0%	
Probe Linearity	2.4%	0.10	Std. Dev.	Normal k=1	1.00	2.4%	
Cable Loss	2.8%	0.12	Specification	Rectangular	1.73	1.6%	
Frequency Analyzer	5.0%	0.21	Specification	Rectangular	1.73	2.9%	
System Repeatability	5.0%	0.21	Std. Dev.	Normal k=1	1.00	5.0%	
WD Repeatability	9.0%	0.37	Std. Dev.	Normal k=1	1.00	9.0%	
Positioner Accuracy	1.0%	0.04	Specification	Rectangular	1.73	0.6%	
Combined standard uncertainty, uc (k=1)						17.7%	0.71
Expanded uncertainty (k=2), 95% confidence level					35.3%	1.31	

Table 7-1 Uncertainty Estimation Table

Notes:

1. Test equipments are calibrated according to techniques outlined in NIS81, NIS3003 and NIST Tech Note 1297.

2. All equipments have traceability according to NIST. Measurement Uncertainties are defined in further detail in

NIS 81 and NIST Tech Note 1297 and UKAS M3003.

Measurement uncertainty reflects the quality and accuracy of a measured result as compared to the true value. Such statements are generally required when stating results of measurements so that it is clear to the intended audience that the results may differ when reproduced by different facilities. Measurement results vary due to the measurement uncertainty of the instrumentation, measurement technique, and test engineer. Most uncertainties are calculated using the tolerances of the instrumentation used in the measurement setup variability, and the technique used in performing the test. While not generally included, the variability of the equipment under test also figures into the overall measurement (so-called Type A uncertainty). This may mean that the Hearing Aid compatibility tests may have to be repeated by taking down the test setup and resetting it up so that there are a statistically significant number of repeat measurements to identify the measurement uncertainty. By combining the repeat measurement results with that of the instrumentation chain using the technique contained in NIS 81 and NIS 3003, the overall measurement uncertainty was estimated.

FCC ID: A3LSMJ337P		HAC (T-COIL) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Dage 26 of 47
1M1910220168-01.A3L	10/28/2019 - 10/29/2019	Portable Handset		Page 26 of 47
© 2019 PCTEST Engineering Laboratory. Inc.				

REV 3.3.M 08/13/2019

EQUIPMENT LIST 8.

Table 8-1 **Equipment List**

Manufacturer	Model	Description	Cal Date	Cal Interval	Cal Due	Serial Number
Control Company	4040	Temperature / Humidity Monitor	2/28/2018	Biennial	2/28/2020	150761911
Dell	Latitude E6540	SoundCheck Acoustic Analyzer Laptop	9/6/2018	Biennial	9/6/2020	2655082910
Listen	SoundConnect	Microphone Power Supply	9/6/2018	Biennial	9/6/2020	0899-PS150
RME	Fireface UC	Soundcheck Acoustic Analyzer External Audio Interface	9/6/2018	Biennial	9/6/2020	23792992
Rohde & Schwarz	CMW500	Wideband Radio Communication Tester	1/30/2019	Annual	1/30/2020	162125
Rohde & Schwarz	CMW500	Radio Communication tester	5/17/2019	Annual	5/17/2020	128635
Seekonk	NC-100	Torque Wrench (8" lb)	5/10/2018	Biennial	5/10/2020	21053
TEM	Axial T-Coil Probe	Axial T-Coil Probe	9/19/2018	Biennial	9/19/2020	TEM-1123
TEM	Radial T-Coil Probe	Radial T-Coil Probe	9/19/2018	Biennial	9/19/2020	TEM-1129
TEM	Helmholtz Coil	Helmholtz Coil	10/10/2018	Biennial	10/10/2020	SBI 1052
TEM		HAC System Controller with Software	N/A		N/A	N/A
TEM		HAC Positioner	N/A		N/A	N/A

FCC ID: A3LSMJ337P		HAC (T-COIL) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Dega 07 of 47
1M1910220168-01.A3L	10/28/2019 - 10/29/2019	Portable Handset		Page 27 of 47
© 2019 PCTEST Engineering Laboratory, Inc.				REV 3.3.M

08/13/2019

9. TEST DATA

FCC ID: A3LSMJ337P		HAC (T-COIL) TEST REPORT	SAMSUNG	Approved by: Quality Manager	
Filename:	Test Dates:	DUT Type:		Dama 00 of 47	
1M1910220168-01.A3L	10/28/2019 - 10/29/2019	Portable Handset		Page 28 of 47	
© 2019 PCTEST Engineering Laboratory, Inc.					

REV 3.3.M 08/13/2019

10/28/2019



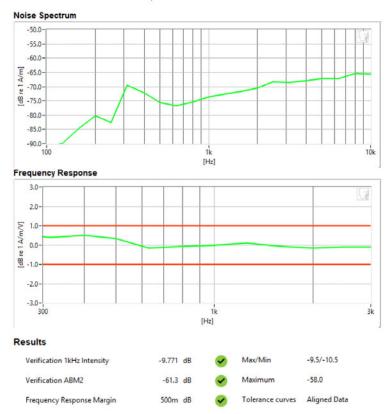
DUT: HH Coil – SN: SBI 1052

Type: HH Coil Serial: SBI 1052

Measurement Standard: ANSI C63.19-2011

Equipment:

Probe: Axial T-Coil Probe – SN: TEM-1123; Calibrated: 09/19/2018
 Helmholtz Coil – SN: SBI 1052; Calibrated: 10/10/2018



PCTEST 2019

FCC ID: A3LSMJ337P		HAC (T-COIL) TEST REPORT	SAMSUNG	Approved by: Quality Manager	
Filename:	Test Dates:	DUT Type:		Dama 00 of 47	
1M1910220168-01.A3L	10/28/2019 - 10/29/2019	Portable Handset		Page 29 of 47	
© 2019 PCTEST Engineering Laboratory, Inc.				REV 3.3.M	

10/28/2019



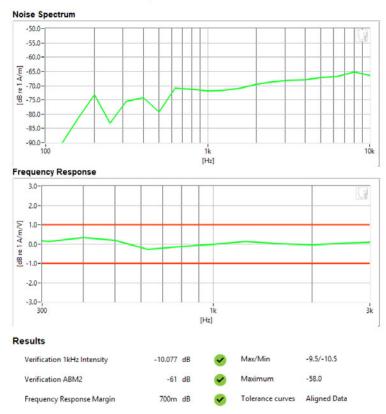
DUT: HH Coil - SN: SBI 1052

Type: HH Coil Serial: SBI 1052

Measurement Standard: ANSI C63.19-2011

Equipment:

Probe: Radial T-Coil Probe – SN: TEM-1129; Calibrated: 09/19/2018
 Helmholtz Coil – SN: SBI 1052; Calibrated: 10/10/2018



PCTEST 2019

FCC ID: A3LSMJ337P		HAC (T-COIL) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Dega 20 of 47
1M1910220168-01.A3L	10/28/2019 - 10/29/2019	Portable Handset		Page 30 of 47
© 2019 PCTEST Engineering	REV 3.3.M			

10/28/2019



PCTEST Hearing-Aid Compatibility Facility

DUT: A3LSMJ337P

Type: Portable Handset Serial: 58046

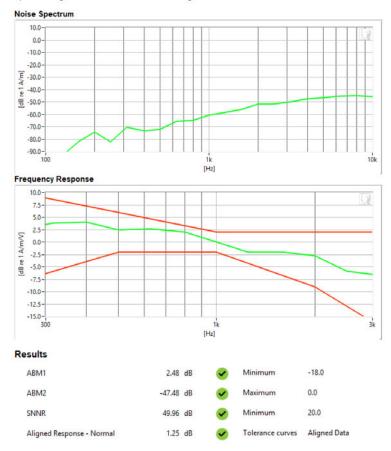
Measurement Standard: ANSI C63.19-2011

Equipment:

Probe: Axial T-Coil Probe - SN: TEM-1123; Calibrated: 09/19/2018

Test Configuration:

- Mode: LTE FDD Band 4
- Bandwidth: 20MHz
- Channel: 20175
- Speech Signal: 3GPP2 Normal Test Signal



PCTEST 2019

FCC ID: A3LSMJ337P		HAC (T-COIL) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Dega 21 of 47
1M1910220168-01.A3L	10/28/2019 - 10/29/2019	Portable Handset		Page 31 of 47
© 2019 PCTEST Engineering Laboratory, Inc.				

10/29/2019



PCTEST Hearing-Aid Compatibility Facility

DUT: A3LSMJ337P

Type: Portable Handset Serial: 58046

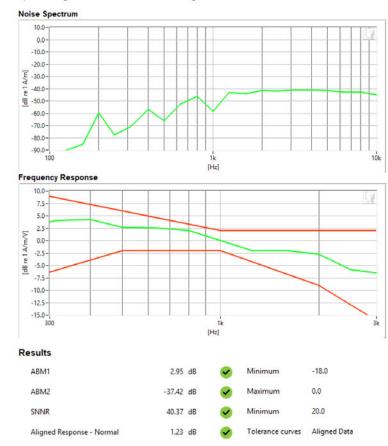
Measurement Standard: ANSI C63.19-2011

Equipment:

Probe: Axial T-Coil Probe - SN: TEM-1123; Calibrated: 09/19/2018

Test Configuration:

- Mode: LTE TDD Band 41 (PC2)
- Bandwidth: 10MHz
- Channel: 40620
- Speech Signal: 3GPP2 Normal Test Signal



PCTEST 2019

FCC ID: A3LSMJ337P		HAC (T-COIL) TEST REPORT	SAMSUNG	Approved by: Quality Manager	
Filename:	Test Dates:	DUT Type:		Daga 22 of 47	
1M1910220168-01.A3L	10/28/2019 - 10/29/2019	Portable Handset		Page 32 of 47	
© 2019 PCTEST Engineering Laboratory, Inc.					

10/29/2019



PCTEST Hearing-Aid Compatibility Facility

DUT: A3LSMJ337P

Type: Portable Handset

Serial: 58046

Measurement Standard: ANSI C63.19-2011

Equipment:

Probe: Radial T-Coil Probe – SN: TEM-1129; Calibrated: 09/19/2018

Test Configuration:

- Mode: LTE FDD Band 4
- Bandwidth: 20MHz
- Channel: 20175





PCTEST 2019

FCC ID: A3LSMJ337P		HAC (T-COIL) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Dega 22 of 47
1M1910220168-01.A3L	10/28/2019 - 10/29/2019	Portable Handset		Page 33 of 47
© 2019 PCTEST Engineering Laboratory, Inc.				

10/29/2019



PCTEST Hearing-Aid Compatibility Facility

DUT: A3LSMJ337P

Type: Portable Handset Serial: 58046

Measurement Standard: ANSI C63.19-2011

Equipment:

Probe: Radial T-Coil Probe - SN: TEM-1129; Calibrated: 09/19/2018

Test Configuration:

- Mode: LTE TDD Band 41 (PC2)
- · Bandwidth: 10MHz
- Channel: 40185

Noise Spectrum



PCTEST 2019

FCC ID: A3LSMJ337P		HAC (T-COIL) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Dega 24 of 47
1M1910220168-01.A3L	10/28/2019 - 10/29/2019	Portable Handset		Page 34 of 47
© 2019 PCTEST Engineering Laboratory, Inc.				

10. CALIBRATION CERTIFICATES

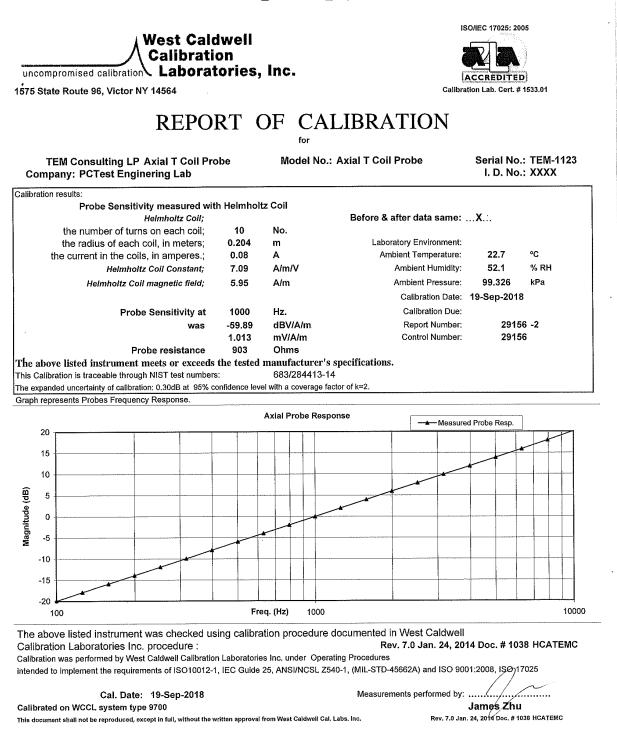
FCC ID: A3LSMJ337P		HAC (T-COIL) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Demo 25 of 47
1M1910220168-01.A3L	10/28/2019 - 10/29/2019	Portable Handset		Page 35 of 47
© 2019 PCTEST Engineering Laboratory, Inc.				

REV 3.3.M 08/13/2019

West (Caldwell Ca	libration Labora	itories Inc.	
Certi	ificate	of Calib	oration	
		for		æ
	AXIA Manufactured	L T COIL PROBE by: TEM CONSU	LTING LP	1000 1000 1000 1000 1000 1000 1000 100
	Model No: Serial No:	AXIAL T COI TEM-1123	L PROBE	
	Calibration R			
		Submitted By:		
	Customer:	Andrew Harwell		11.000
	Company: Address:	PCTest Engineering Lab 6660-B Dobbin Road)	
		Columbia	MD 21045	
submitter.		t met the following specificati rocedure No. AXIAL T C 1	TEM C	
Upon receipt for Cali			12/4/2018	
Within	1 (X)		12/4/2018	
			4t	1000 1000 1000 1000 1000 1000
The information supp	lied relates to the cal	e attached Report of Calibrat ibrated item listed above.		
		alibration control system mee 540-1, IEC Guide 25, ISO 90		
				Ĩ
				11.00
Note: With this Certificate	, Report of Calibration Is	included. Appro	oved by: Fc	
Calibration Date:	19-Sep-18	Felix	Christopher (QA Mgr.)	
Certificate No:	29156 -2		ISO/IEC 17025:2005	
QA Doc. #1051 Rev. 2.0 10/1/01		ificate Page 1 of 1		
	Calibration		ACCREDITED	

FCC ID: A3LSMJ337P		HAC (T-COIL) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Dego 26 of 47
1M1910220168-01.A3L	10/28/2019 - 10/29/2019	Portable Handset		Page 36 of 47
© 2019 PCTEST Engineering Laboratory, Inc.				

HCATEMC_TEM-1123_Sep-19-2018



Page 1 of 2

FCC ID: A3LSMJ337P		HAC (T-COIL) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Dega 27 of 47
1M1910220168-01.A3L	10/28/2019 - 10/29/2019	Portable Handset		Page 37 of 47
© 2019 PCTEST Engineering Laboratory, Inc.				

REV 3.3.M 08/13/2019

HCATEMC_TEM-1123_Sep-19-2018

West Caldwell Calibration Laboratories Inc.

1575 State Route 96, Victor NY 14564

Tel. (585) 586-3900 FAX (585) 586-4327

Calibration Data Record for

TEM Consulting LP Axial T Coil Probe Company: PCTest Engineering Lab

Model No.: Axial T Coil Probe

Serial No.: TEM-1123

Test	Function	Tolerance		Measured values		
				Before	Out	Remarks
1.0	Probe Sensitivity at	1000 Hz.	dBV/A/m	-59.89		
	· · ·		dB			
2.0	Probe Level Linearity		6	6.03		
		Ref. (0 dB)	0	0.00		
•			-6	-6.03		
			-12	-12.05		
	19 ²¹ (1929)	······	Hz			
3.0	Probe Frequency Response		100	-19.9		
			126	-17.9		
			158	-15.9		
			200	-13.9		
			251	-11.9		
			316	-9.9		
			398	-7.9		
			501	-6.0		
			631	-4.0		
			794	-2.0		
		Ref. (0 dB)	1000	0.0		
			1259	2.0		
			1585	4.0		
			1995	5.9		
			2512	7.9		
			3162	9.9		
			3981	11.9		
			5012	13.9		
•			6310	15.9		
			7943	18.0		
			10000	20.1		

Instruments used for a	alibration:		Date of Cal.	Traceablity No.	Due Date
HP	34401A	S/N US360641	25-Jul-2018	,287708	25-Jul-2019
HP	34401A	S/N US361024	25-Jul-2018	,287708	25-Jul-2019
HP	33120A	S/N US360437	25-Jul-2018	,287708	25-Jul-2019
B&K	2133	S/N 1583254	25-Jul-2018	683/284413-14	25-Jul-2019

Cal. Date: 19-Sep-2018

Calibrated on WCCL system type 9700

This document shall not be reproduced, except in full, without the written approval from West Caldwell Cal. Labs. Inc.

Tested by: James Zhu

Rev. 7.0 Jan. 24, 2014 Doc. # 1038 HCATEMC

Page 2 of 2

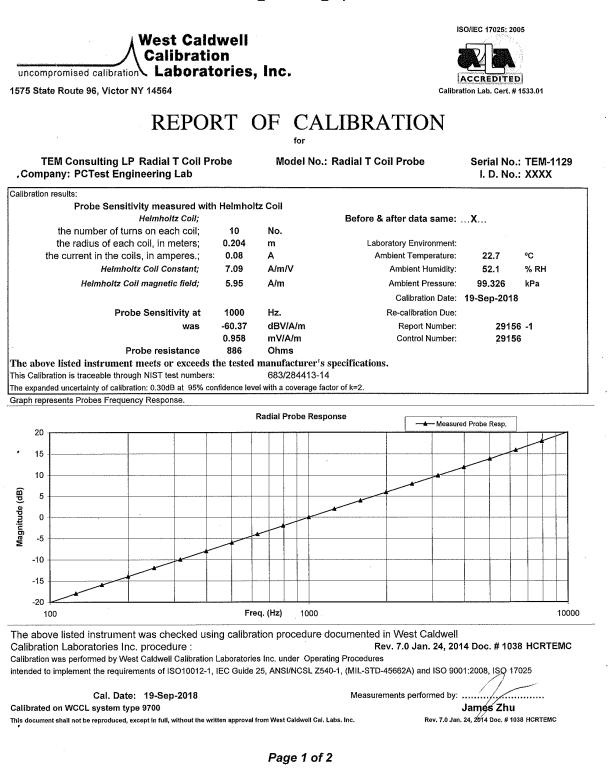
FCC ID: A3LSMJ337P		HAC (T-COIL) TEST REPORT	SAMSUNG	Approved by: Quality Manager	
Filename:	Test Dates:	DUT Type:		Dega 29 of 47	
1M1910220168-01.A3L	10/28/2019 - 10/29/2019	Portable Handset		Page 38 of 47	
© 2019 PCTEST Engineering Laboratory. Inc.					

08/13/2019

We	st Caldwell Ca	libration La	aboratori	es Inc.	
\sim		6.0	1•1		
Cer	tificate	$0\mathbf{I}\mathbf{C}\mathbf{a}$	libra	ation	
		for			
		AL T COIL PROBE		TD	
	Manufactured Model No:	RAD	CONSULTING		
	Serial No: Calibration R		(-1129 6		
		Submitted By:			
	Customer:	Andrew Harwe			11. 1000
	Company: Address:	PCTest Engine 6660-B Dobbin	Road		
		Columbia	r	AD 21045	
National Institut	rument was calibrated to the of Standards and Techno ertifies that the instrument	ology or to accepted	values of natura	l physical constants.	
West Caldwell C	Calibration Laboratories P	rocedure No. R	ADIAL T TEM C	/- M	
Upon receipt for	Calibration, the instrume	nt was found to be:		VAA 12/4/2018	
) D	Vithin (X)			12/4/2018	
	indicated specification. Se	•			
West Caldwell C	supplied relates to the cal Calibration Laboratories' c	alibration control sy	stem meets the r		
10012-1 MIL-ST	D-45662A, ANSI/NCSL Z	540-1, IEC Guide 25	5, ISO 9001:2008	and ISO 17025.	
Note: With this Cert	ificate, Report of Callbration is	included.	Approved by	FC	
Calibration Date	e: 19-Sep-18		Felix Christo	pher (QA Mgr.)	
Certificate No:	29156 -1			17025:2005	
QA Doc. #1051 Rev. 2.0	0010	ificate Page 1 of 1			Ś
	West Caldwell		<u> </u>		
	ation Laboratories Victor, NY 14564, U.S.A.	, Inc.	- MARCHERSON	REDITED ab. Cert. # 1533.01	
State State					

FCC ID: A3LSMJ337P		HAC (T-COIL) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Dega 20 of 47
1M1910220168-01.A3L	10/28/2019 - 10/29/2019	Portable Handset		Page 39 of 47
© 2019 PCTEST Engineering	g Laboratory, Inc.			REV 3.3.M

HCRTEMC_TEM-1129_Sep-19-2018



FCC ID: A3LSMJ337P	PCTEST	HAC (T-COIL) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Page 40 of 47
1M1910220168-01.A3L	10/28/2019 - 10/29/2019	Portable Handset		Page 40 01 47
© 2019 PCTEST Engineering Laboratory, Inc.				

REV 3.3.M 08/13/2019

HCRTEMC_TEM-1129_Sep-19-2018

West Caldwell Calibration Laboratories Inc.

1575 State Route 96, Victor NY 14564 Tel. (585) 586-3900 FAX (585) 586-4327

Calibration Data Record

TEM Consulting LP Radial T Coil Probe Company: PCTest Engineering Lab ^{for} Model No.: Radial T Coil Probe

Serial No.: TEM-1129

Test	Function	Tolerance		Measured values		
				Before	Out	Remarks
1.0	Probe Sensitivity at	1000 Hz.	dBV/A/m	-60.37		
			dB			
2.0	Probe Level Linearity		6	6.03		
		Ref. (0 dB)	0	0.00		
			-6	-6.03		
			-12	-12.05		
			Hz			
3.0	Probe Frequency Response		100	-20.0		
			126	-17.9		
			158	-15.9		
			200	-14.0		
			251	-12.0		
			316	-10.0		
			398	-8.0		
			501	-6.0		
			631	-4.0		
			794	-2.0		
		Ref. (0 dB)	1000	0.0		
			1259	2.0		
			1585	4.0		
			1995	6.0		
			2512	7.9		
			3162	9.9		
			3981	11.9		
			5012	13.9		1
			6310	15.9		1
			7943	18.0		
			10000	20.1		

Instruments used for a	calibration:		Date of Cal.	Traceability No.	Due Date
' HP	34401A	S/N US360641	25-Jul-2018	,287708	25-Jul-2019
HP	34401A	S/N US361024	25-Jul-2018	,287708	25-Jul-2019
HP	33120A	S/N US360437	25-Jul-2018	.287708	25-Jul-2019
B&K	2133	S/N 1583254	25-Jul-2018	683/284413-14	25-Jul-2019

Cal. Date: 19-Sep-2018

Calibrated on WCCL system type 9700

This document shall not be reproduced, except in full, without the written approval from West Caldwell Cal. Labs. Inc.

Tested by: James Zhu

Rev. 7.0 Jan. 24, 2014 Doc. # 1038 HCRTEMC

Page 2 of 2

FCC ID: A3LSMJ337P		HAC (T-COIL) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Page 41 of 47
1M1910220168-01.A3L	10/28/2019 - 10/29/2019	Portable Handset		Page 41 01 47
© 2019 PCTEST Engineering	REV 3.3.M			

^{08/13/2019}

11. CONCLUSION

The measurements indicate that the wireless communications device complies with the HAC limits specified in accordance with the ANSI C63.19 Standard and FCC WT Docket No. 01-309 RM-8658. Precise laboratory measures were taken to assure repeatability of the tests. The tested device complies with the requirements in respect to all parameters specific to the test. The test results and statements relate only to the item(s) tested.

The measurement system and techniques presented in this evaluation are proposed in the ANSI standard as a means of best approximating wireless device compatibility with a hearing-aid. The literature is under continual re-construction.

FCC ID: A3LSMJ337P		HAC (T-COIL) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Page 42 of 47
1M1910220168-01.A3L	10/28/2019 - 10/29/2019	Portable Handset		
© 2019 PCTEST Engineering Laboratory, Inc.				

REV 3.3.M 08/13/2019

© 2019 PCTEST Engineering Laboratory, Inc. All rights reserved. Unless otherwise specified, no part of this report may be reproduced or utilized in any part, form or by any means, formor by any means, formor or by any mean

12. REFERENCES

- 1. ANSI C63.19-2011, American National Standard for Methods of Measurement of Compatibility between Wireless communication devices and Hearing Aids.", New York, NY, IEEE, May 2011
- 2. FCC Office of Engineering and Technology KDB, "285076 D01 HAC Guidance v05," September 13, 2017
- 3. FCC Office of Engineering and Technology KDB, "285076 D02 T-Coil Testing for CMRS IP v03," September 13, 2017
- 4. FCC Public Notice DA 06-1215, Wireless Telecommunications Bureau and Office of Engineering and Technology Clarify Use of Revised Wireless Phone Hearing Aid Compatibility Standard, June 6, 2006
- 5. FCC 3G Review Guidance, Laboratory Division OET FCC, May/June 2006
- 6. Berger, H. S., "Compatibility Between Hearing Aids and Wireless Devices," Electronic Industries Forum, Boston, MA, May, 1997
- 7. Berger, H. S., "Hearing Aid and Cellular Phone Compatibility: Working Toward Solutions," Wireless Telephones and Hearing Aids: New Challenges for Audiology, Gallaudet University, Washington, D.C., May, 1997 (To be reprinted in the American Journal of Audiology).
- 8. Berger, H. S., "Hearing Aid Compatibility with Wireless Communications Devices, " IEEE International Symposium on Electromagnetic Compatibility, Austin, TX, August, 1997.
- Bronaugh, E. L., "Simplifying EMI Immunity (Susceptibility) Tests in TEM Cells," in the 1990 IEEE International Symposium on Electromagnetic Compatibility Symposium Record, Washington, D.C., August 1990, pp. 488-491
- 10. Byme, D. and Dillon, H., The National Acoustics Laboratory (NAL) New Procedure for Selecting the Gain and Frequency Response of a Hearing Aid, Ear and Hearing 7:257-265, 1986.
- Crawford, M. L., "Measurement of Electromagnetic Radiation from Electronic Equipment using TEM Transmission Cells," U.S. Department of Commerce, National Bureau of Standards, NBSIR 73-306, Feb. 1973.
- Crawford, M. L., and Workman, J. L., "Using a TEM Cell for EMC Measurements of Electronic Equipment," U.S. Department of Commerce, National Bureau of Standards. Technical Note 1013, July 1981.
- 13. EHIMA GSM Project, Development phase, Project Report (1st part) Revision A. Technical-Audiological Laboratory and Telecom Denmark, October 1993.
- 14. EHIMA GSM Project, Development phase, Part II Project Report. Technical-Audiological Laboratory and Telecom Denmark, June 1994.
- 15. EHIMA GSM Project Final Report, Hearing Aids and GSM Mobile Telephones: Interference Problems, Methods of Measurement and Levels of Immunity. Technical-Audiological Laboratory and Telecom Denmark, 1995.
- 16. HAMPIS Report, Comparison of Mobile phone electromagnetic near field with an upscaled electromagnetic far field, using hearing aid as reference, 21 October 1999.
- 17. Hearing Aids/GSM, Report from OTWIDAM, Technical-Audiological Laboratory and Telecom Denmark, April 1993.
- 18. IEEE 100, The Authoritative Dictionary of IEEE Standards Terms, Seventh Edition.
- Joyner, K. H, et. al., Interference to Hearing Aids by the New Digital Mobile Telephone System, Global System for Mobile (GSM) Communication Standard, National Acoustic Laboratory, Australian Hearing Series, Sydney 1993.
- Joyner, K. H., et. al., Interference to Hearing Aids by the Digital Mobile Telephone System, Global System for Mobile Communications (GSM), NAL Report #131, National Acoustic Laboratory, Australian Hearing Series, Sydney, 1995.
- 21. Kecker, W. T., Crawford, M. L., and Wilson, W. A., "Contruction of a Transverse Electromagnetic Cell", U.S. Department of Commerce, National Bureau of Standards, Technical Note 1011, Nov. 1978.
- Konigstein, D., and Hansen, D., "A New Family of TEM Cells with enlarged bandwidth and Optimized working Volume," in the Proceedings of the 7th International Symposium on EMC, Zurich, Switzerland, March 1987; 50:9, pp. 127-132.

FCC ID: A3LSMJ337P		HAC (T-COIL) TEST REPORT	SAMSUNG	Approved by: Quality Manager	
Filename:	Test Dates:	DUT Type:		Daga 42 of 47	
1M1910220168-01.A3L	10/28/2019 - 10/29/2019	Portable Handset		Page 43 of 47	
© 2019 PCTEST Engineering Laboratory, Inc.					

© 2019 PCTEST Engineering Laboratory, Inc. All rights reserved. Unless otherwise specified, no part of this report may be reproduced or utilized in any part, form or by any means, formor by any means, formor or by any mean

- Kuk, F., and Hjorstgaard, N. K., "Factors affecting interference from digital cellular telephones," Hearing Journal, 1997; 50:9, pp 32-34.
- 24. Ma, M. A., and Kanda, M., "Electromagnetic Compatibility and Interference Metrology," U.S. Department of Commerce, National Bureau of Standards, Technical Note 1099, July 1986, pp. 17-43.
- Ma, M. A., Sreenivashiah, I., and Chang, D. C., "A Method of Determining the Emission and Susceptibility Levels of Electrically Small Objects Using a TEM Cell," U.S. Department of Commerce, National Bureau of Standards, Technial Note 1040, July 1981.
- 26. McCandless, G. A., and Lyregaard, P. E., Prescription of Gain/Output (POGO) for Hearing Aids, Hearing Instruments 1:16-21, 1983
- 27. Skopec, M., "Hearing Aid Electromagnetic Interference from Digital Wireless Telephones, "IEEE Transactions on Rehabilitation Engineering, vol. 6, no. 2, pp. 235-239, June 1998.
- Technical Report, GSM 05.90, GSM EMC Considerations, European Telecommunications Standards Institute, January 1993.
- 29. Victorian, T. A., "Digital Cellular Telephone Interference and Hearing Aid Compatibility—an Update," Hearing Journal 1998; 51:10, pp. 53-60
- 30. Wong, G. S. K., and Embleton, T. F. W., eds., AIP Handbook of Condenser Microphones: Theory, Calibration and Measurements, AIP Press.

FCC ID: A3LSMJ337P		HAC (T-COIL) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Page 44 of 47
1M1910220168-01.A3L	10/28/2019 - 10/29/2019	Portable Handset		
© 2019 PCTEST Engineering Laboratory. Inc.				